
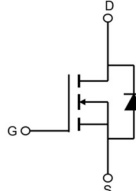


## Description

<b>Features</b> <ul style="list-style-type: none"> <li>● 500V, 18A  <math>R_{DS(ON)} &lt; 0.33\Omega @ V_{GS} = 10V</math></li> <li>● Fast Switching</li> <li>● Improved dv/dt Capability</li> </ul>	<b>Application</b> <ul style="list-style-type: none"> <li>● Load Switch</li> <li>● PWM Application</li> <li>● Power management</li> </ul> <p style="text-align: center;">100% UIS 100% <math>\Delta V_{ds}</math></p>
 TO-220F	 Schematic Diagram

## Package Marking and Ordering Information

Device Marking	Device	OUTLINE	Device Package	TUBE (PCS)	Inner Box (PCS)	Per Carton (PCS)
VSM18N50-TF	VSM18N50	TUBE	TO-220F	50	1,000	8,000

## Absolute Maximum Ratings (T<sub>C</sub>=25°C unless otherwise specified)

Symbol	Parameter	Max.	Units
V <sub>DSS</sub>	Drain-Source Voltage	500	V
V <sub>GSS</sub>	Gate-Source Voltage	±30	V
I <sub>D</sub>	Continuous Drain Current	T <sub>C</sub> = 25°C	18
		T <sub>C</sub> = 100°C	12
I <sub>DM</sub>	Pulsed Drain Current <sup>note1</sup>	72	A
E <sub>AS</sub>	Single Pulsed Avalanche Energy <sup>note2</sup>	583	mJ
P <sub>D</sub>	Power Dissipation	T <sub>C</sub> = 25°C	38.5
R <sub>θJC</sub>	Thermal Resistance, Junction to Case	3.3	°C/ W
R <sub>θJA</sub>	Thermal Resistance, Junction to Ambient	62.5	°C/ W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range	-55 to +150	°C

**Electrical Characteristics** ( $T_J=25^{\circ}\text{C}$  unless otherwise specified)

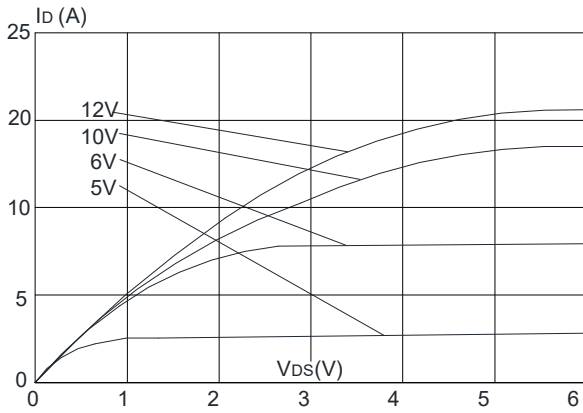
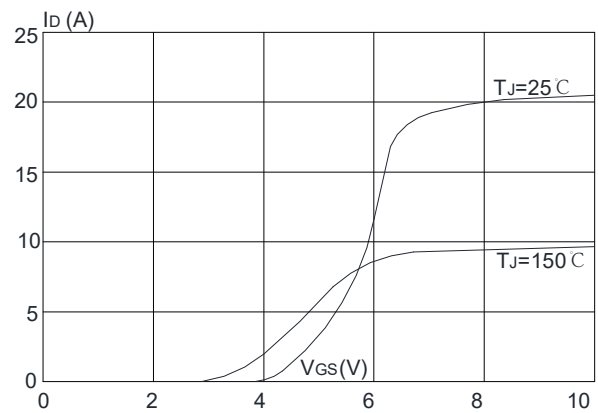
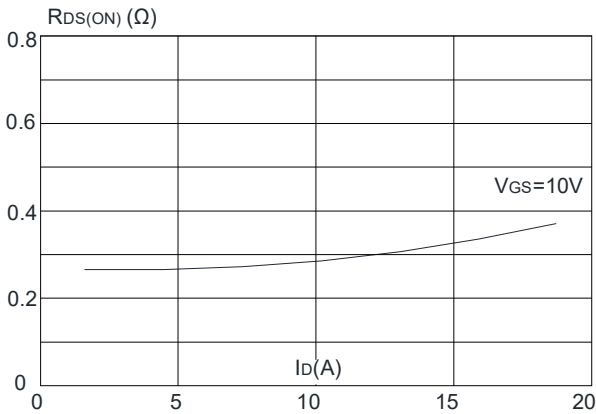
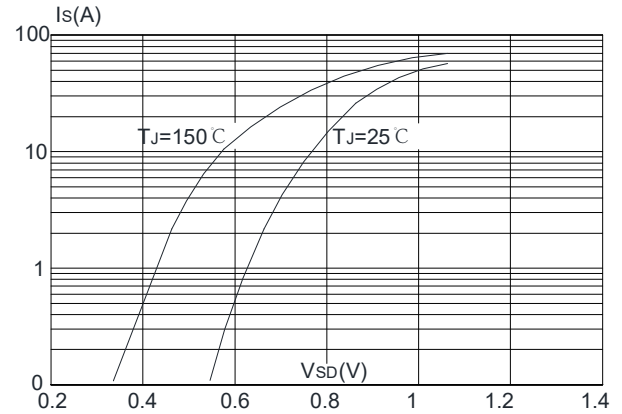
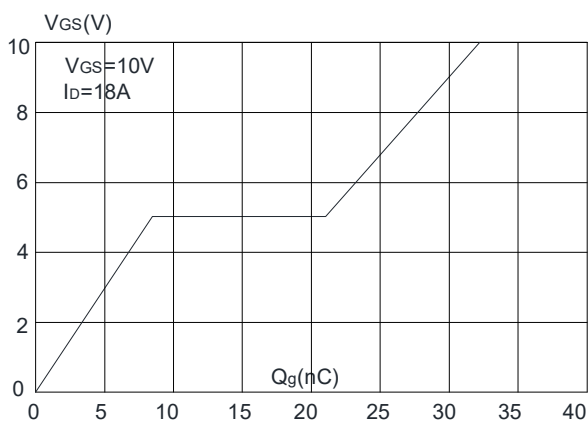
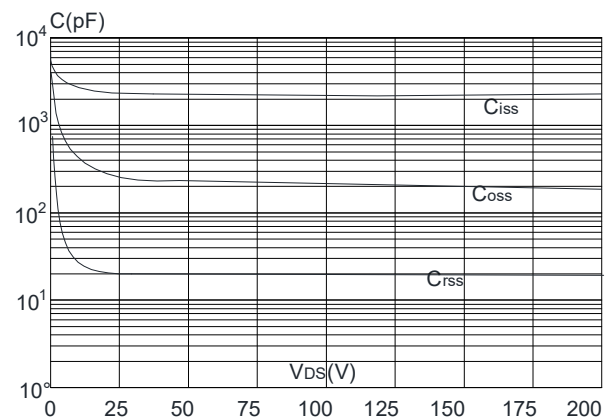
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
<b>Off Characteristic</b>						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	500	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 500V, V_{GS} = 0V,$ $T_J = 25^{\circ}\text{C}$	-	-	1	$\mu A$
$I_{GSS}$	Gate to Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 30V$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	2	3	4	V
$R_{DS(on)}$	Static Drain-Source on-Resistance <small>note3</small>	$V_{GS} = 10V, I_D = 9A$	-	0.28	0.33	$\Omega$
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS} = 25V, V_{GS} = 0V,$ $f = 1.0\text{MHz}$	-	2118	-	pF
$C_{oss}$	Output Capacitance		-	235	-	pF
$C_{riss}$	Reverse Transfer Capacitance		-	20	-	pF
$Q_g$	Total Gate Charge	$V_{DD} = 400V, I_D = 18A,$ $V_{GS} = 10V$	-	32	-	nC
$Q_{gs}$	Gate-Source Charge		-	8.5	-	nC
$Q_{gd}$	Gate-Drain("Miller") Charge		-	14	-	nC
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = 250V, I_D = 18A,$ $R_G = 25\Omega$	-	40	-	ns
$t_r$	Turn-on Rise Time		-	150	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	65	-	ns
$t_f$	Turn-off Fall Time		-	80	-	ns
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_S$	Maximum Continuous Drain to Source Diode Forward Current		-	-	18	A
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current		-	-	72	A
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_{SD} = 18A$	-	-	1.4	V
$t_{rr}$	Reverse Recovery Time	$V_{GS} = 0V, I_S = 18A,$ $di/dt = 100A/\mu s$	-	490	-	ns
$Q_{rr}$	Reverse Recovery Charge		-	5.0	-	$\mu C$

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

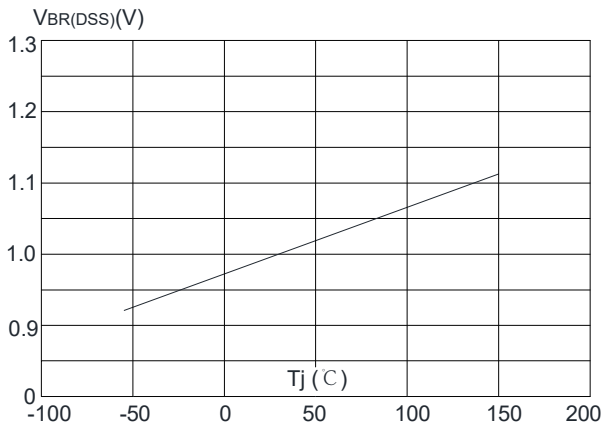
 2. EAS condition:  $T_J = 25^{\circ}\text{C}, V_{DD} = 50V, V_G = 10V, L = 10\text{mH}, I_{AS} = 10.8A$ 

 3. Pulse Test: Pulse Width  $\leq 300\mu s$ , Duty Cycle  $\leq 1\%$

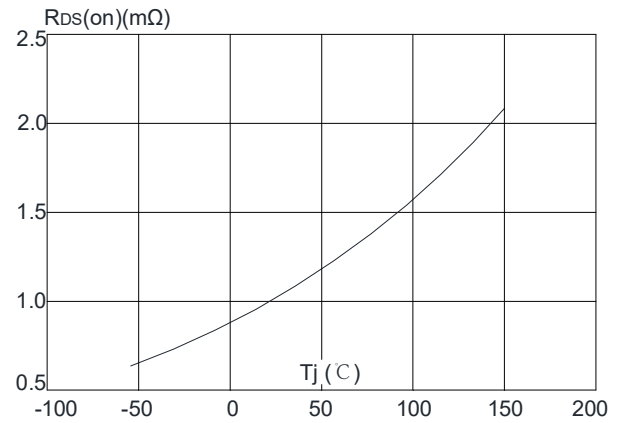
## Typical Performance Characteristics

**Figure 1: Output Characteristics**

**Figure 2: Typical Transfer Characteristics**

**Figure 3: On-resistance vs. Drain Current**

**Figure 4: Body Diode Characteristics**

**Figure 5: Gate Charge Characteristics**

**Figure 6: Capacitance Characteristics**


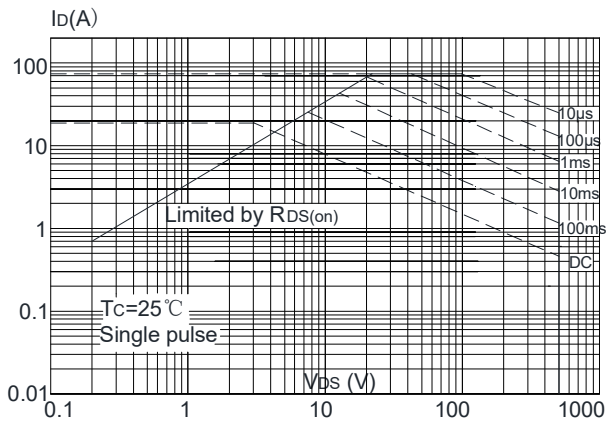
**Figure 7: Normalized Breakdown Voltage vs. Junction Temperature**



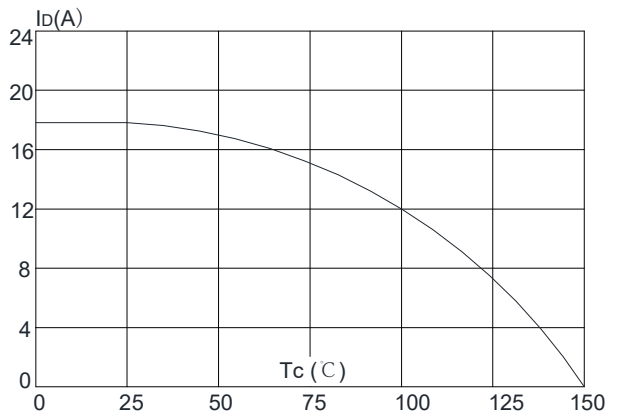
**Figure 8: Normalized on Resistance vs. Junction Temperature**



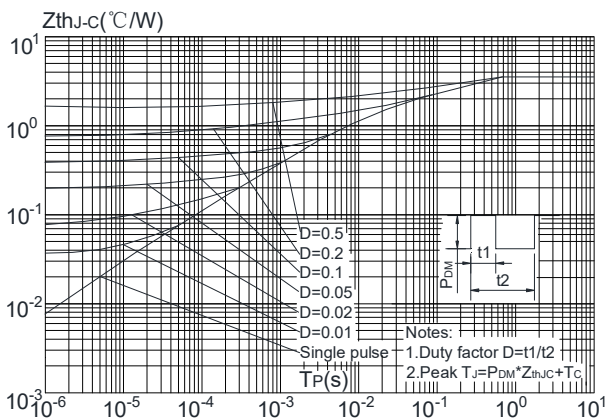
**Figure 9: Maximum Safe Operating Area**



**Figure 10: Maximum Continuous Drain Current vs. Case Temperature**



**Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case**



## Test Circuit

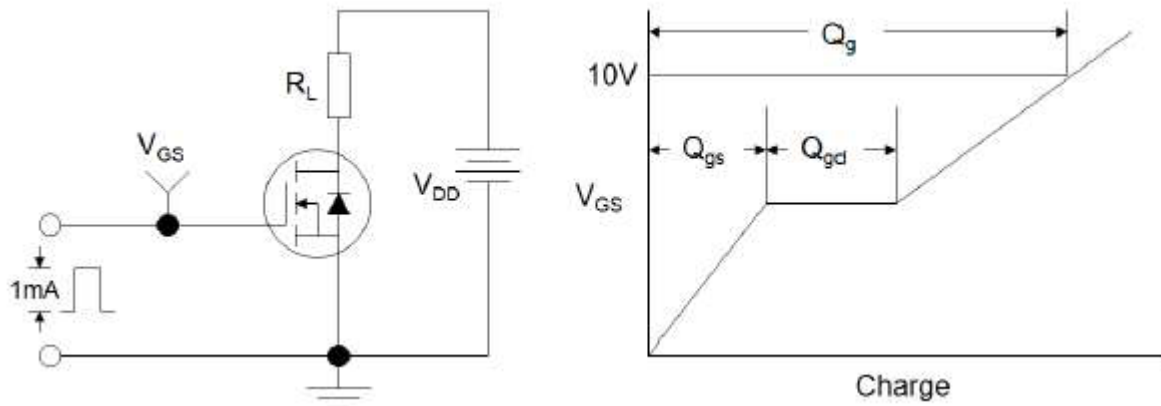


Figure 1: Gate Charge Test Circuit & Waveform

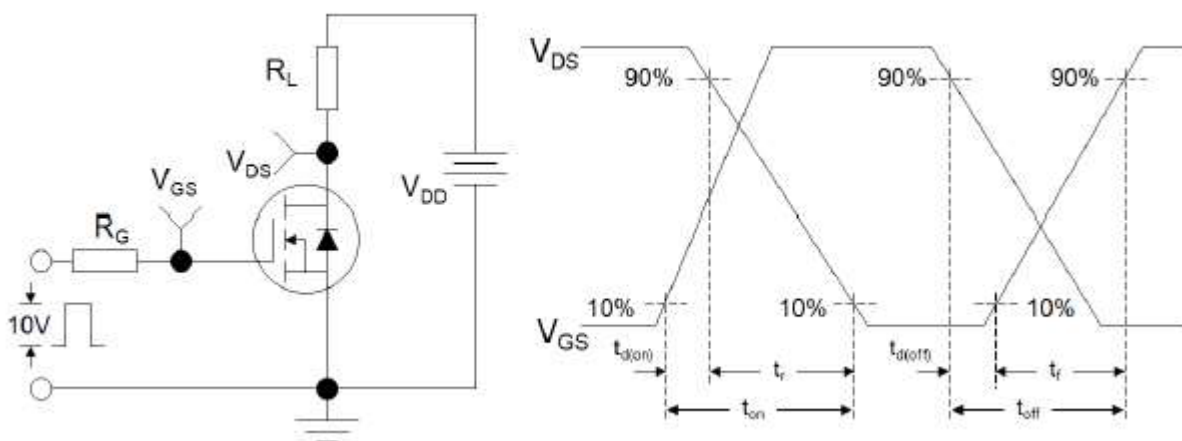


Figure 2: Resistive Switching Test Circuit & Waveforms

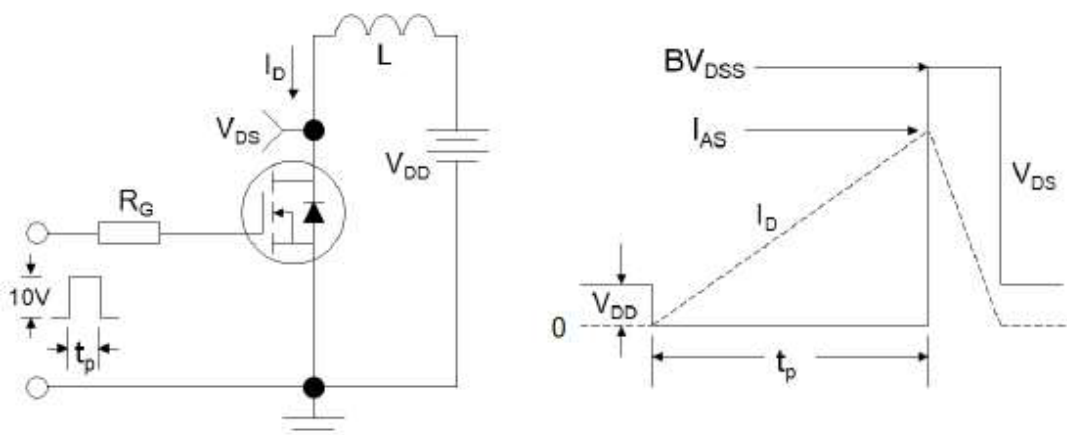


Figure 3: Unclamped Inductive Switching Test Circuit & Waveforms